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### Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### **Details**

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	57
Number of Gates	3000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	80-TQFP
Supplier Device Package	80-VQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/a40mx02-vqg80">https://www.e-xfl.com/product-detail/microchip-technology/a40mx02-vqg80</a>



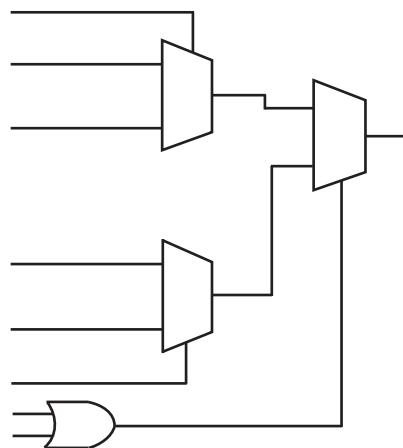
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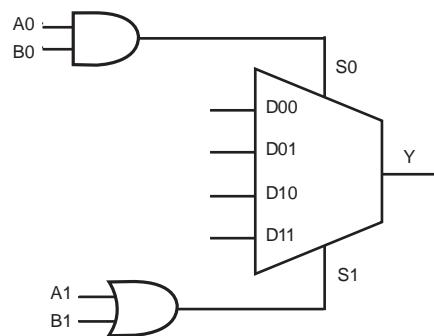
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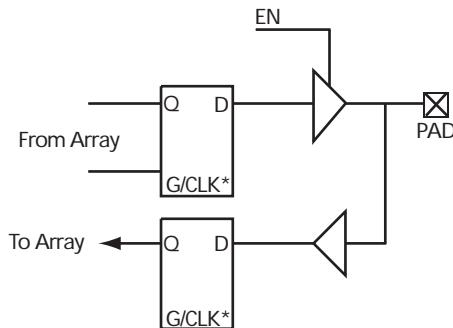
**Figure 2 • 42MX C-Module Implementation**

The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in [Figure 4](#), page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

**Figure 3 • 42MX C-Module Implementation**

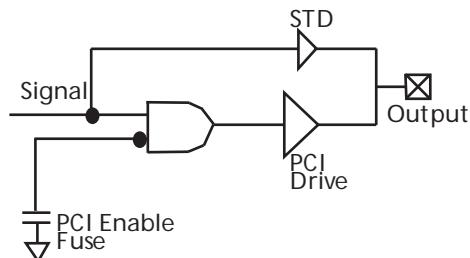
Designer software development tools provide a design library of I/O macro functions that can implement all I/O configurations supported by the MX FPGAs.

**Figure 10 • 42MX I/O Module**



**Note:** \*Can be configured as a Latch or D Flip-Flop (Using C-Module)

**Figure 11 • PCI Output Structure of A42MX24 and A42MX36 Devices**



### 3.3 Other Architectural Features

The following sections cover other architectural features of 40MX and 42MX FPGAs.

#### 3.3.1 Performance

MX devices can operate with internal clock frequencies of 250 MHz, enabling fast execution of complex logic functions. MX devices are live on power-up and do not require auxiliary configuration devices and thus are an optimal platform to integrate the functionality contained in multiple programmable logic devices. In addition, designs that previously would have required a gate array to meet performance can be integrated into an MX device with improvements in cost and time-to-market. Using timing-driven place-and-route (TDPR) tools, designers can achieve highly deterministic device performance.

#### 3.3.2 User Security

Microsemi FuseLock provides robust security against design theft. Special security fuses are hidden in the fabric of the device and protect against unauthorized users attempting to access the programming and/or probe interfaces. It is virtually impossible to identify or bypass these fuses without damaging the device, making Microsemi antifuse FPGAs protected with the highest level of security available from both invasive and noninvasive attacks.

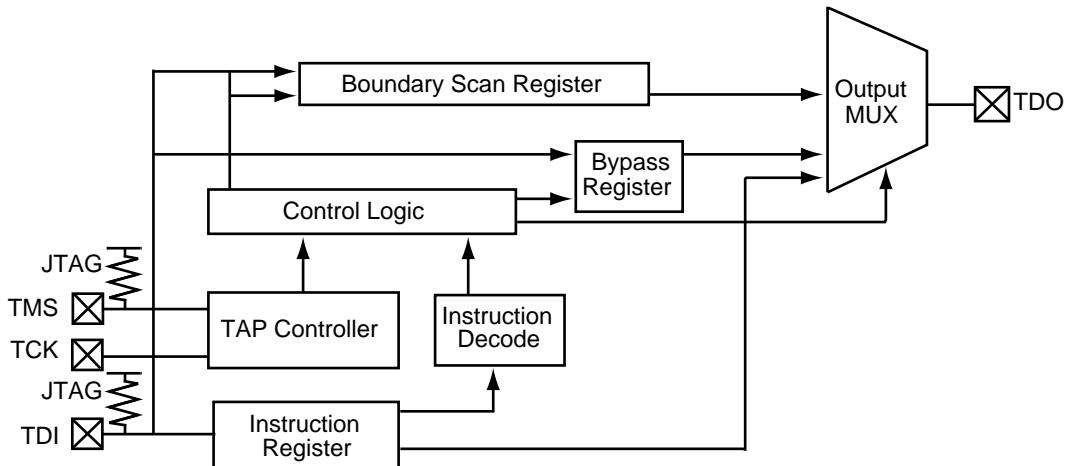
Special security fuses in 40MX devices include the Probe Fuse and Program Fuse. The former disables the probing circuitry while the latter prohibits further programming of all fuses, including the Probe Fuse. In 42MX devices, there is the Security Fuse which, when programmed, both disables the probing circuitry and prohibits further programming of the device.

#### 3.3.3 Programming

Device programming is supported through the Silicon Sculptor series of programmers. Silicon Sculptor is a compact, robust, single-site and multi-site device programmer for the PC. With standalone software, Silicon Sculptor is designed to allow concurrent programming of multiple units from the same PC.

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

**Figure 14 • 42MX IEEE 1149.1 Boundary Scan Circuitry**



**Table 9 • Test Access Port Descriptions**

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

**Table 10 • Supported BST Public Instructions**

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

**Table 23 • DC Specification (5.0 V PCI Signaling)<sup>1</sup>**

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
C <sub>IN</sub>	Input Pin Capacitance			10	—	10	pF
C <sub>CLK</sub>	CLK Pin Capacitance		5	12	—	10	pF
L <sub>PIN</sub>	Pin Inductance			20	—	< 8 nH <sup>4</sup>	nH

1. PCI Local Bus Specification, Version 2.1, Section 4.2.1.1.

2. Maximum rating for VCCI –0.5 V to 7.0 V

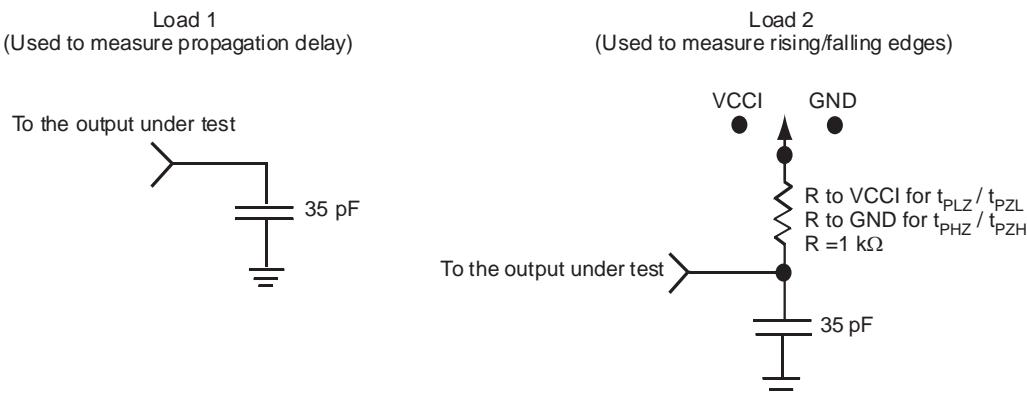
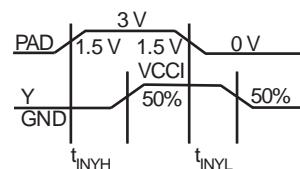
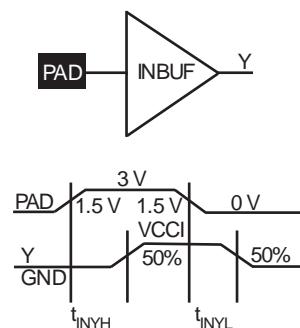
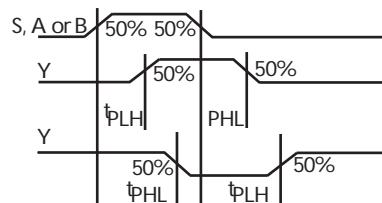
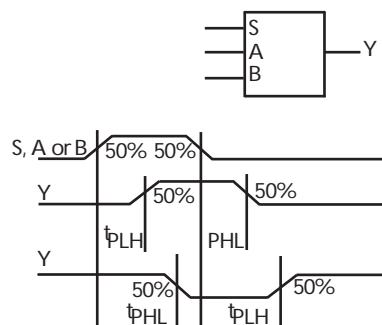
3. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V.

4. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

**Table 24 • AC Specifications (5.0V PCI Signaling)\***

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
ICL	Low Clamp Current	–5 < VIN ≤ –1	–25 + (VIN +1) /0.015		–60	–10	mA
Slew (r)	Output Rise Slew Rate	0.4 V to 2.4 V load	1		5	1.8	2.8
Slew (f)	Output Fall Slew Rate	2.4 V to 0.4 V load	1		5	2.8	4.3

Note: \*PCI Local Bus Specification, Version 2.1, Section 4.2.1.2.

**Figure 22 • AC Test Loads****Figure 23 • Input Buffer Delays****Figure 24 • Module Delays**

**Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, V<sub>CC</sub> = 3.0 V, T<sub>J</sub> = 70°C)**

<b>Parameter / Description</b>	<b>-3 Speed</b>		<b>-2 Speed</b>		<b>-1 Speed</b>		<b>Std Speed</b>		<b>-F Speed</b>		<b>Units</b>
	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.6	5.3	5.6	7.0	9.8					ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width	4.6	5.3	5.6	7.0	9.8					ns
t <sub>A</sub>	Flip-Flop Clock Input Period	6.8	7.8	8.9	10.4	14.6					ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency (FO = 128)		109	101	92	80	48	MHz			
<b>Input Module Propagation Delays</b>											
t <sub>I<sub>NYH</sub></sub>	Pad-to-Y HIGH		1.0	1.1	1.3	1.5	2.1	ns			
t <sub>I<sub>NYL</sub></sub>	Pad-to-Y LOW		0.9	1.0	1.1	1.3	1.9	ns			

**Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T<sub>J</sub> = 70°C)**

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
<b>CMOS Output Module Timing<sup>5</sup></b>											
t <sub>DH</sub>	Data-to-Pad HIGH		3.1		3.5		3.9		4.6		6.4 ns
t <sub>DHL</sub>	Data-to-Pad LOW		2.4		2.6		3.0		3.5		4.9 ns
t <sub>ENZH</sub>	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3 ns
t <sub>ENZL</sub>	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.8 ns
t <sub>ENHZ</sub>	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7 ns
t <sub>ENLZ</sub>	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9 ns
t <sub>GLH</sub>	G-to-Pad HIGH		4.9		5.4		6.2		7.2		10.1 ns
t <sub>GHL</sub>	G-to-Pad LOW		4.9		5.4		6.2		7.2		10.1 ns
t <sub>LSU</sub>	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0	ns
t <sub>LH</sub>	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0	ns
t <sub>LCO</sub>	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.5		6.1		6.9		8.1		11.3 ns
t <sub>ACO</sub>	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0 ns
d <sub>TLH</sub>	Capacitive Loading, LOW to HIGH	0.04		0.04		0.04		0.05		0.07	ns/pF
d <sub>THL</sub>	Capacitive Loading, HIGH to LOW	0.03		0.03		0.03		0.04		0.06	ns/pF

- For dual-module macros, use t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, t<sub>CO</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, or t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>SUD</sub>, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
- Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
- Delays based on 35 pF loading

**Table 43 • A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T<sub>J</sub> = 70°C)**

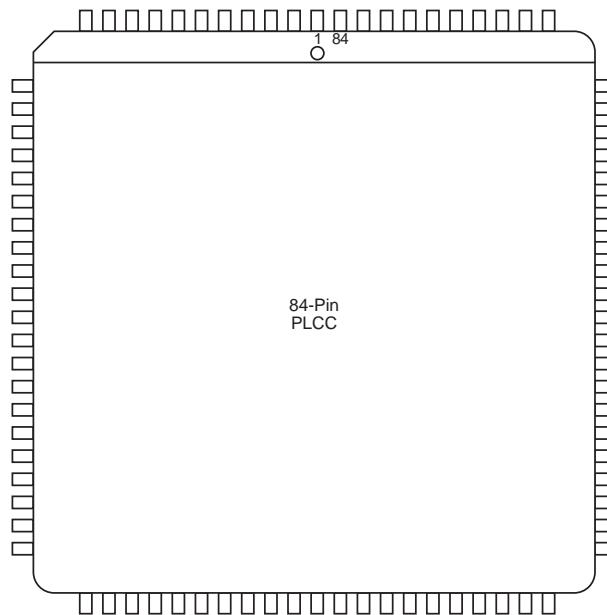
Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
<b>Logic Module Combinatorial Functions<sup>1</sup></b>											
t <sub>PD</sub>	Internal Array Module Delay	2.0		1.8		2.1		2.5		3.4	ns
t <sub>PDD</sub>	Internal Decode Module Delay	1.1		2.2		2.5		3.0		4.2	ns
<b>Logic Module Predicted Routing Delays<sup>2</sup></b>											
t <sub>RD1</sub>	FO = 1 Routing Delay	1.7		1.3		1.4		1.7		2.3	ns
t <sub>RD2</sub>	FO = 2 Routing Delay	2.0		1.6		1.8		2.1		3.0	ns
t <sub>RD3</sub>	FO = 3 Routing Delay	1.1		2.0		2.2		2.6		3.7	ns
t <sub>RD4</sub>	FO = 4 Routing Delay	1.5		2.3		2.6		3.1		4.3	ns
t <sub>RD5</sub>	FO = 8 Routing Delay	1.8		3.7		4.2		5.0		7.0	ns

**Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, TJ = 70°C)**

<b>Parameter / Description</b>		<b>-3 Speed</b>		<b>-2 Speed</b>		<b>-1 Speed</b>		<b>Std Speed</b>		<b>-F Speed</b>	
		<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>	<b>Min.</b>	<b>Max.</b>
<b>Synchronous SRAM Operations (continued)</b>											
t <sub>ADH</sub>	Address/Data Hold Time	0.0	0.0	0.0	0.0	0.0	0.0	0.0	0.0	ns	
t <sub>RENSU</sub>	Read Enable Set-Up	0.9	1.0	1.1	1.3	1.8	ns				
t <sub>RENH</sub>	Read Enable Hold	4.8	5.3	6.0	7.0	9.8	ns				
t <sub>WENSU</sub>	Write Enable Set-Up	3.8	4.2	4.8	5.6	7.8	ns				
t <sub>WENH</sub>	Write Enable Hold	0.0	0.0	0.0	0.0	0.0	ns				
t <sub>BENS</sub>	Block Enable Set-Up	3.9	4.3	4.9	5.7	8.0	ns				
t <sub>BENH</sub>	Block Enable Hold	0.0	0.0	0.0	0.0	0.0	ns				
<b>Asynchronous SRAM Operations</b>											
t <sub>RPD</sub>	Asynchronous Access Time	11.3	12.6	14.3	16.8	23.5	ns				
t <sub>RDADV</sub>	Read Address Valid	12.3	13.7	15.5	18.2	25.5	ns				
t <sub>ADSU</sub>	Address/Data Set-Up Time	2.3	2.5	2.8	3.4	4.8	ns				
t <sub>ADH</sub>	Address/Data Hold Time	0.0	0.0	0.0	0.0	0.0	ns				
t <sub>RENSUA</sub>	Read Enable Set-Up to Address Valid	0.9	1.0	1.1	1.3	1.8	ns				
t <sub>RENHA</sub>	Read Enable Hold	4.8	5.3	6.0	7.0	9.8	ns				
t <sub>WENSU</sub>	Write Enable Set-Up	3.8	4.2	4.8	5.6	7.8	ns				
t <sub>WENH</sub>	Write Enable Hold	0.0	0.0	0.0	0.0	0.0	ns				
t <sub>DOH</sub>	Data Out Hold Time	1.8	2.0	2.1	2.5	3.5	ns				
<b>Input Module Propagation Delays</b>											
t <sub>INPY</sub>	Input Data Pad-to-Y	1.4	1.6	1.8	2.1	3.0	ns				
t <sub>INGO</sub>	Input Latch Gate-to-Output	2.0	2.2	2.5	2.9	4.1	ns				
t <sub>INH</sub>	Input Latch Hold	0.0	0.0	0.0	0.0	0.0	ns				
t <sub>INSU</sub>	Input Latch Set-Up	0.7	0.7	0.8	1.0	1.4	ns				
t <sub>ILA</sub>	Latch Active Pulse Width	6.5	7.3	8.2	9.7	13.5	ns				

**Table 48 • PL68**

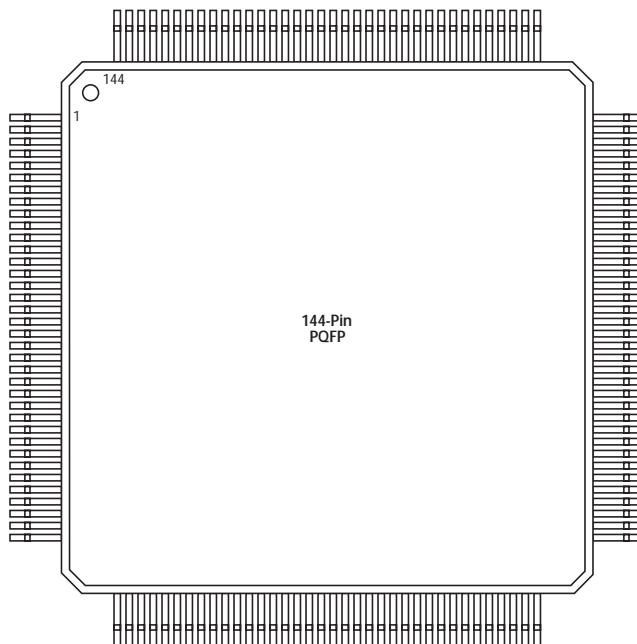
<b>PL68</b>		
<b>Pin Number</b>	<b>A40MX02 Function</b>	<b>A40MX04 Function</b>
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	GND	GND
67	I/O	I/O
68	I/O	I/O

**Figure 40 • PL84****Table 49 • PL84**

<b>PL84</b>				
<b>Pin Number</b>	<b>A40MX04 Function</b>	<b>A42MX09 Function</b>	<b>A42MX16 Function</b>	<b>A42MX24 Function</b>
1	I/O	I/O	I/O	I/O
2	I/O	CLKB, I/O	CLKB, I/O	CLKB, I/O
3	I/O	I/O	I/O	I/O
4	VCC	PRB, I/O	PRB, I/O	PRB, I/O
5	I/O	I/O	I/O	WD, I/O
6	I/O	GND	GND	GND
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	WD, I/O
9	I/O	I/O	I/O	WD, I/O

**Table 49 • PL84**

Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	I/O	DCLK, I/O	DCLK, I/O	DCLK, I/O
11	I/O	I/O	I/O	I/O
12	NC	MODE	MODE	MODE
13	I/O	I/O	I/O	I/O
14	I/O	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	I/O	I/O	I/O	I/O
18	GND	I/O	I/O	I/O
19	GND	I/O	I/O	I/O
20	I/O	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	VCCA	VCCI	VCCI
23	I/O	VCCI	VCCA	VCCA
24	I/O	I/O	I/O	I/O
25	VCC	I/O	I/O	I/O
26	VCC	I/O	I/O	I/O
27	I/O	I/O	I/O	I/O
28	I/O	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	I/O	I/O	I/O	I/O
31	I/O	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	VCC	I/O	I/O	I/O
34	I/O	I/O	I/O	TMS, I/O
35	I/O	I/O	I/O	TDI, I/O
36	I/O	I/O	I/O	WD, I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	WD, I/O
39	I/O	I/O	I/O	WD, I/O
40	GND	I/O	I/O	I/O
41	I/O	I/O	I/O	I/O
42	I/O	I/O	I/O	I/O
43	I/O	VCCA	VCCA	VCCA
44	I/O	I/O	I/O	WD, I/O
45	I/O	I/O	I/O	WD, I/O
46	VCC	I/O	I/O	WD, I/O

**Figure 42 • PQ144****Table 51 • PQ144**

<b>PQ144</b>	
<b>Pin Number</b>	<b>A42MX09 Function</b>
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

**Table 52 • PQ160**

<b>PQ160</b>			
<b>Pin Number</b>	<b>A42MX09 Function</b>	<b>A42MX16 Function</b>	<b>A42MX24 Function</b>
21	CLKA, I/O	CLKA, I/O	CLKA, I/O
22	I/O	I/O	I/O
23	PRA, I/O	PRA, I/O	PRA, I/O
24	NC	I/O	WD, I/O
25	I/O	I/O	WD, I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	NC	I/O	I/O
29	I/O	I/O	WD, I/O
30	GND	GND	GND
31	NC	I/O	WD, I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	VCCI	VCCI
36	I/O	I/O	WD, I/O
37	I/O	I/O	WD, I/O
38	SDI, I/O	SDI, I/O	SDI, I/O
39	I/O	I/O	I/O
40	GND	GND	GND
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	GND	GND	GND
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	NC	I/O	I/O
53	I/O	I/O	I/O
54	NC	VCCA	VCCA
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	VCCA	VCCA	VCCA

**Table 53 • PQ208**

Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
21	I/O	I/O	I/O
22	GND	GND	GND
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	GND	GND	GND
28	VCCI	VCCI	VCCI
29	VCCA	VCCA	VCCA
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	VCCA	VCCA	VCCA
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	NC	I/O	I/O
42	NC	I/O	I/O
43	NC	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	NC	I/O	I/O
52	GND	GND	GND
53	GND	GND	GND
54	I/O	TMS, I/O	TMS, I/O
55	I/O	TDI, I/O	TDI, I/O
56	I/O	I/O	I/O
57	I/O	WD, I/O	WD, I/O

**Table 53 • PQ208**

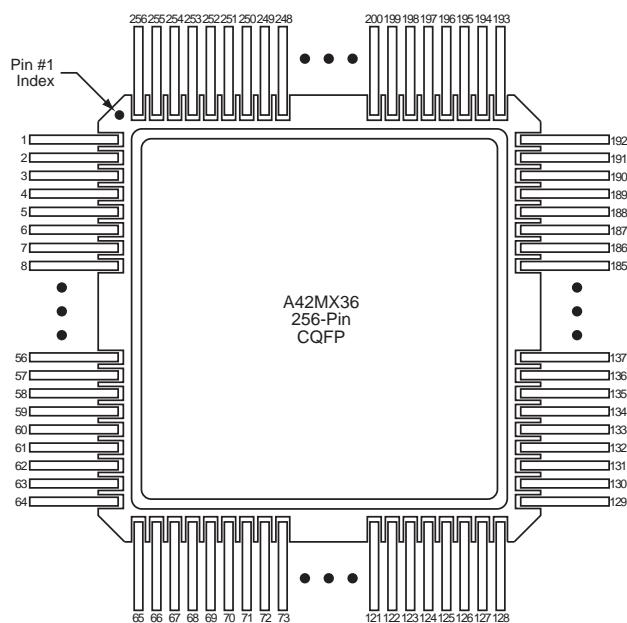
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
169	I/O	WD, I/O	WD, I/O
170	I/O	I/O	I/O
171	NC	I/O	QCLKD, I/O
172	I/O	I/O	I/O
173	I/O	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	I/O	WD, I/O	WD, I/O
177	I/O	WD, I/O	WD, I/O
178	PRA, I/O	PRA, I/O	PRA, I/O
179	I/O	I/O	I/O
180	CLKA, I/O	CLKA, I/O	CLKA, I/O
181	NC	I/O	I/O
182	NC	VCCI	VCCI
183	VCCA	VCCA	VCCA
184	GND	GND	GND
185	I/O	I/O	I/O
186	CLKB, I/O	CLKB, I/O	CLKB, I/O
187	I/O	I/O	I/O
188	PRB, I/O	PRB, I/O	PRB, I/O
189	I/O	I/O	I/O
190	I/O	WD, I/O	WD, I/O
191	I/O	WD, I/O	WD, I/O
192	I/O	I/O	I/O
193	NC	I/O	I/O
194	NC	WD, I/O	WD, I/O
195	NC	WD, I/O	WD, I/O
196	I/O	I/O	QCLKC, I/O
197	NC	I/O	I/O
198	I/O	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	NC	I/O	I/O
202	VCCI	VCCI	VCCI
203	I/O	WD, I/O	WD, I/O
204	I/O	WD, I/O	WD, I/O
205	I/O	I/O	I/O

**Table 54 • PQ240**

<b>PQ240</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

**Table 58 • CQ208**

<b>CQ208</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	I/O
117	I/O
118	I/O
119	I/O
120	I/O
121	I/O
122	I/O
123	I/O
124	I/O
125	I/O
126	GND
127	I/O
128	TCK, I/O
129	LP
130	VCCA
131	GND
132	VCCI
133	VCCA
134	I/O
135	I/O
136	VCCA
137	I/O
138	I/O
139	I/O
140	I/O
141	I/O
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O

**Figure 50 • CQ256****Table 59 • CQ256**

CQ256	
Pin Number	A42MX36 Function
1	NC
2	GND
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	GND
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O

**Table 60 • BG272**

<b>BG272</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
C3	GND
C4	I/O
C5	WD, I/O
C6	I/O
C7	QCLKC, I/O
C8	I/O
C9	I/O
C10	CLKB
C11	PRA, I/O
C12	WD, I/O
C13	I/O
C14	QCLKD, I/O
C15	I/O
C16	WD, I/O
C17	SDI, I/O
C18	I/O
C19	I/O
C20	I/O
D1	I/O
D2	I/O
D3	I/O
D4	I/O
D5	VCCI
D6	I/O
D7	I/O
D8	VCCA
D9	WD, I/O
D10	VCCI
D11	I/O
D12	VCCI
D13	I/O
D14	VCCI
D15	I/O
D16	VCCA
D17	GND
D18	I/O
D19	I/O

**Table 60 • BG272**

<b>BG272</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
D20	I/O
E1	I/O
E2	I/O
E3	I/O
E4	VCCA
E17	VCCI
E18	I/O
E19	I/O
E20	I/O
F1	I/O
F2	I/O
F3	I/O
F4	VCCI
F17	I/O
F18	I/O
F19	I/O
F20	I/O
G1	I/O
G2	I/O
G3	I/O
G4	VCCI
G17	VCCI
G18	I/O
G19	I/O
G20	I/O
H1	I/O
H2	I/O
H3	I/O
H4	VCCA
H17	I/O
H18	I/O
H19	I/O
H20	I/O
J1	I/O
J2	I/O
J3	I/O
J4	VCCI